



# Agenda item 4.2

## Training activities



## Convener training activities

- Details in AMD 4.2
- Pilot training course run in June 2016 (Braunschweig)
- Ten training courses between June 2017 and July 2019
- Two courses this year, April in Ottawa, July in Berlin
- Total of 192 people trained
  
- One more course in November 2019

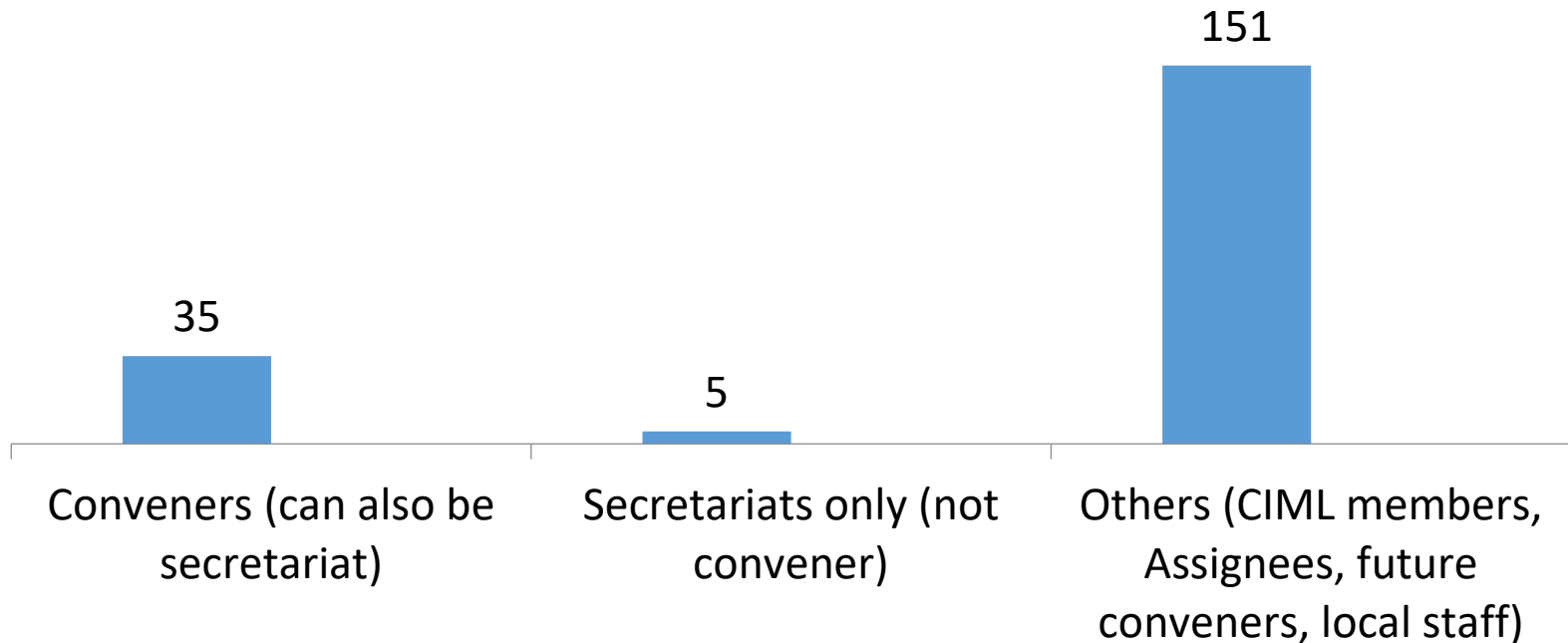


## Convener training courses

When	Where	Trained Countries	Trainees
June 2017	St. Petersburg, Russia	Russia	24
Dec. 2017	Paris (BIML)	France, Netherlands, United Kingdom, Germany	12
Jan. 2018	Sydney, Australia	Australia, New Zealand	14
March 2018	Bratislava, Slovakia	Slovakia, Austria, Czech Republic, Hungary, Poland,	9
March 2018	Paris (BIML)	France, Netherlands, United Kingdom, Slovenia	10
June 2018	Tokyo, Japan	Japan	11
Sept. 2018	Beijing, China	China	48
Nov. 2018	Johannesburg, SA	South Africa, Kenya, Zambia	40
April 2018	Ottawa, Canada	Canada	13
July 2018	Berlin, Germany	Germany, Slovakia	10

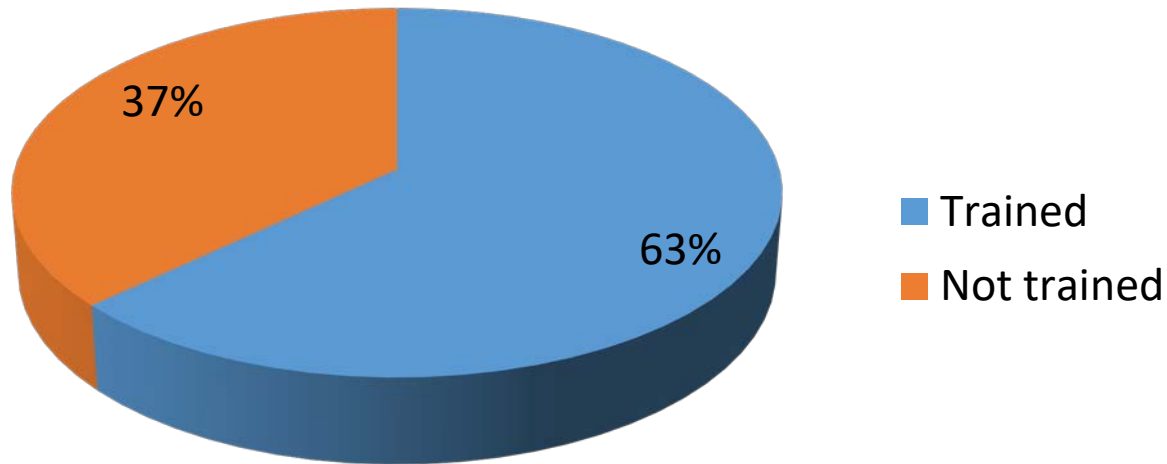


# Individuals trained to October 2019



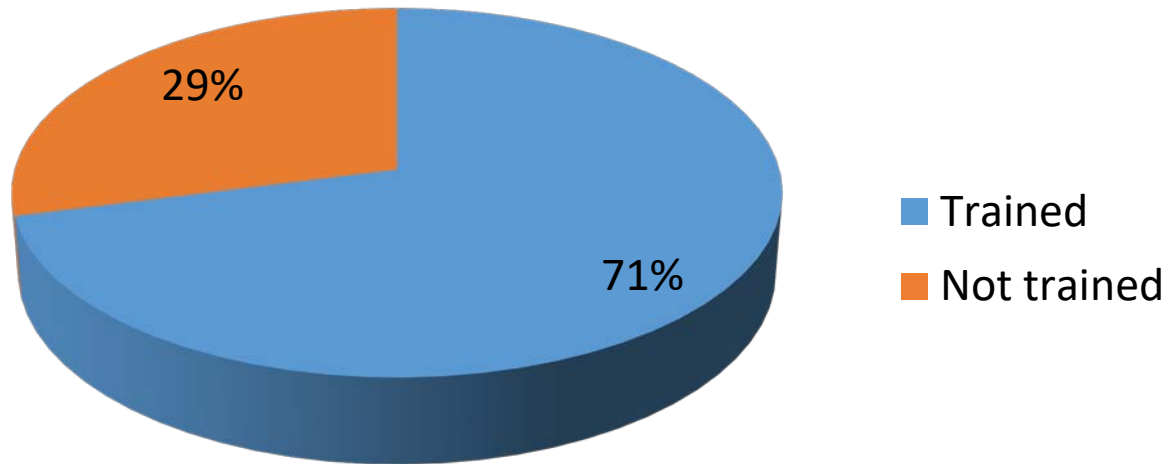


## Of 62 TC/SC secretariats (48 persons)





## Of 47 PG conveners (35 persons)





# Feedback

- Questions/comments received during sessions have improved courses
- Several trainees emailed that courses helped them in their daily work
- Helpful follow-up emails from trainees with questions about procedures
- For two Chinese projects which had been inactive for some years, new conveners appointed just before training produced new CDs within a few weeks of the training, including considerable re-organisation of existing drafts. Since then, the projects' progress has been good
- Conveners of a new German project also made quick progress in advancing their project following the training session in July 2019



## Convener training activities

- Completes initial intensive phase of convener training
- Maintenance still needed
  - For new staff
  - For changes to B 6 procedures
  - For refreshing knowledge





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